



INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet

1

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2

Complete If Known

Application Number

10/074.732

Filing Date

02/13/2002

First Named Inventor

Leo Mathew et al.

Group Art Unit

2815

Examiner Name

Paul E. Brock II

Attorney Docket Number

SC11805TP

Examiner Initials ¹	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
<i>[Handwritten initials]</i>	BA	6,372,559		Crowder et al.	04-16-2002	
<i>[Handwritten initials]</i>	BB	6,300,182		Yu	10-09-2001	
<i>[Handwritten initials]</i>	BC	5,689,127		Chu et al.	11-18-1997	
<i>[Handwritten initials]</i>	BD	4,859,623		Bustin	08-22-1989	
<i>[Large handwritten signature across multiple rows]</i>						

[illegible]

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Signature

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¹ Unique citation designation number. ² See Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English Language Translation is attached.



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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Complete if Known	
		Application Number	10/074,732
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Sheet	2	of	2
		Attorney Docket Number	SC11805TP

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. 1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	BF	YU, BIN et al.; "FinFET Scaling to 10nm Gate Length"; IEEE IEDM; 2002; pages 251-254; IEEE; USA	
	RG	International Search Report	

Examiner Signature		Date Considered	12/7/2004
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